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Micro-structural Stress Modeling of Brittle Materials for Enhanced Performance and Reliability

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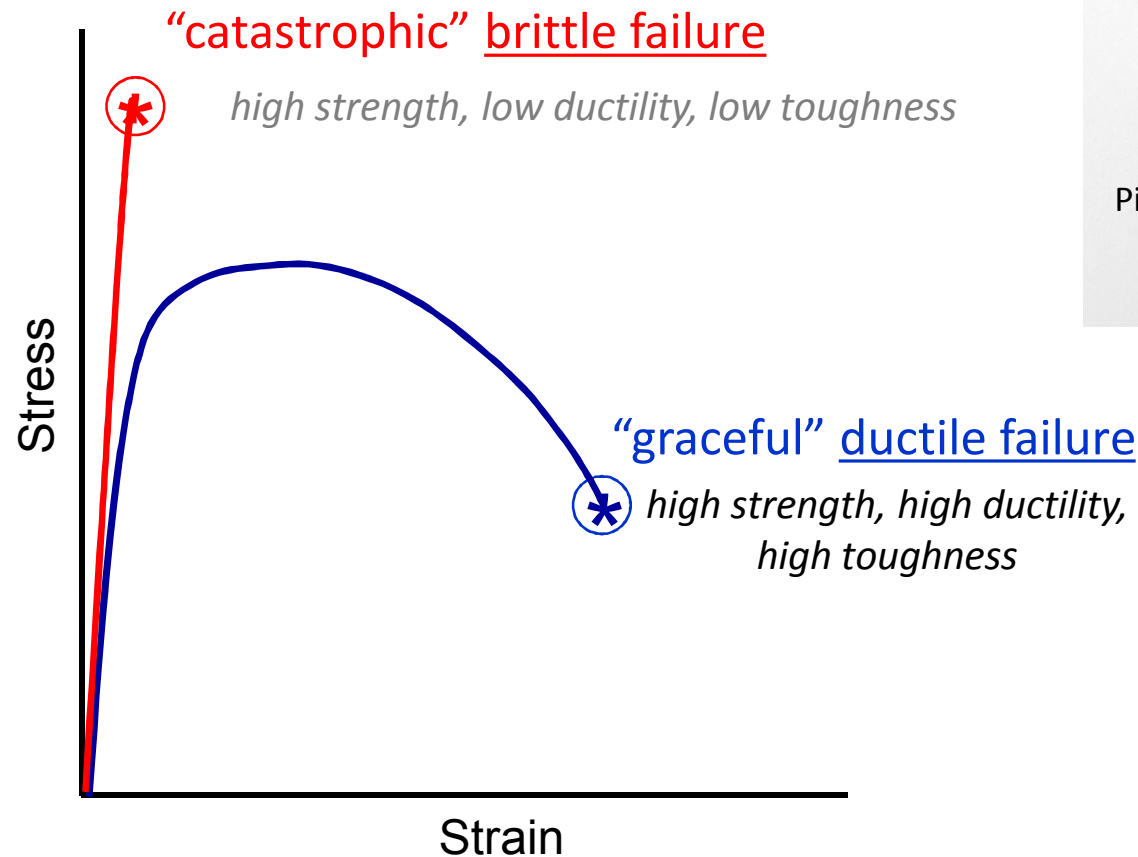


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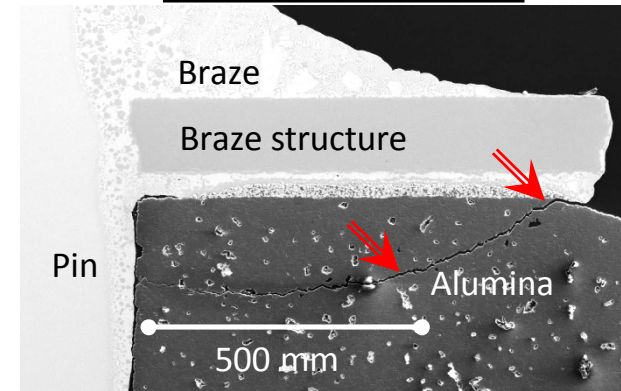


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- Motivation
 - Background
 - Experimental Measurements
 - Modeling
 - Micro-structure meshing
 - Modeling of stresses
 - Future Work

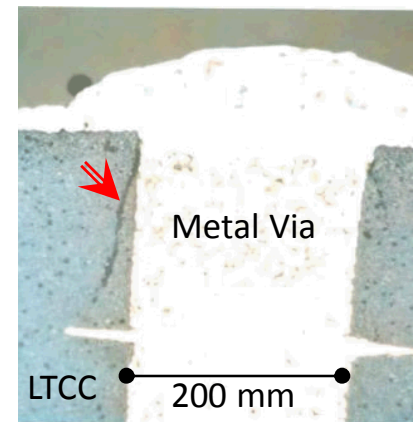
Brittle Materials Failure Presents A Reliability Concern in High Consequence Applications



Electrical Feedthru



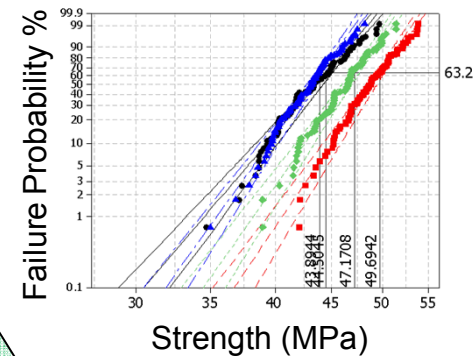
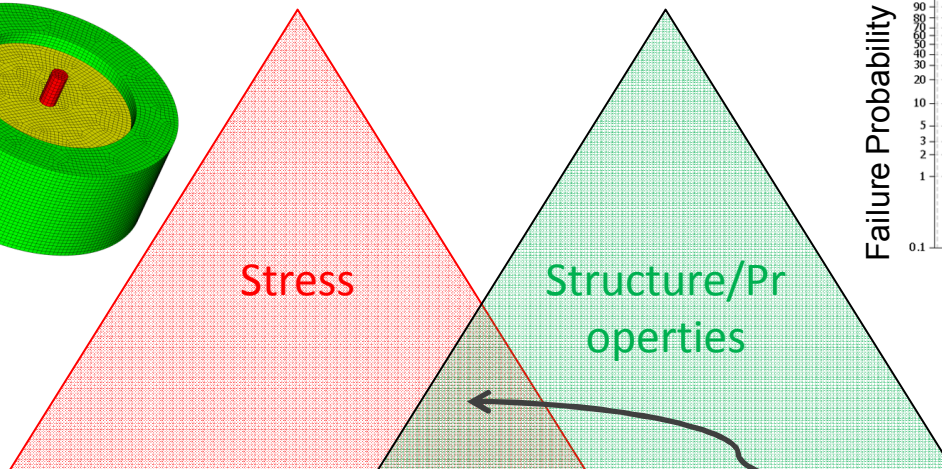
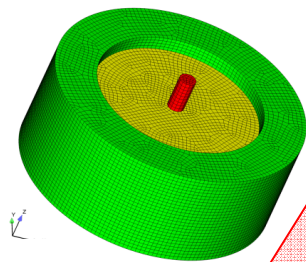
Electronic Substrate



Brittle materials are susceptible to sudden catastrophic failure

Current State: Qualitative Stress-Based Predictions

$$\sigma \sim \sigma_{crit}$$

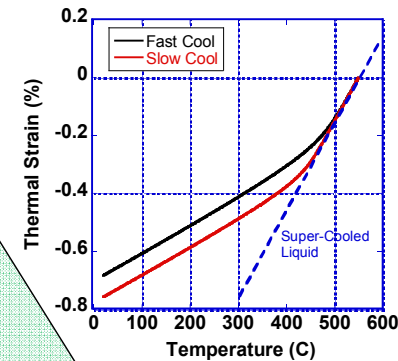
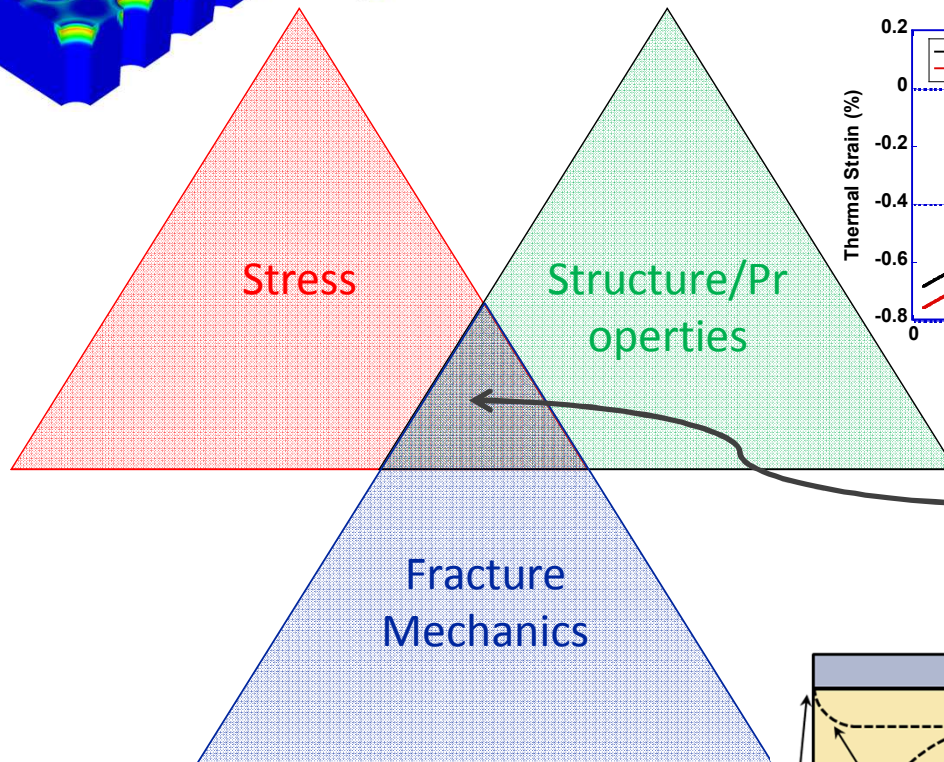
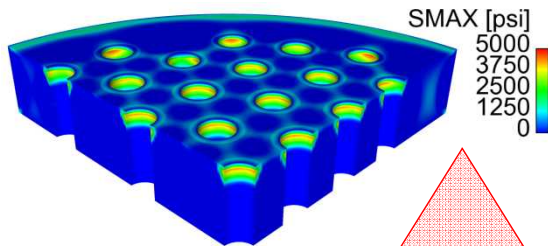


Qualitative prediction
of brittle failure based
on engineering
judgment/experience

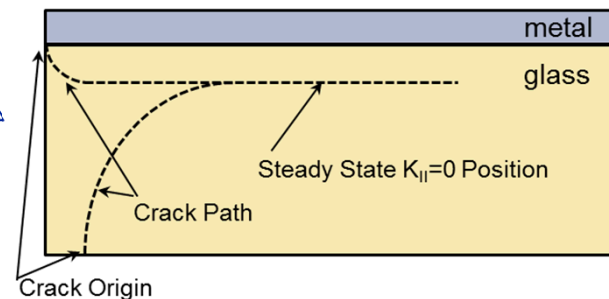
- We Design To Avoid High Stress
- Engineering Judgment Has Deficiencies
 - Limited by practical experience
 - Neglects flaws/flaw populations
 - Does not incorporate fracture mechanics

Future State: Quantitative Mechanics-Based Prediction of Brittle Failure & Reliability

$$K \sim \sigma a^{1/2} \sim K_{IC}$$



Quantitative mechanics-based brittle failure prediction



Sandia Has A Research & Development Program Sandia National Laboratories That Addresses The Gaps To Predict Brittle Failure

Vision

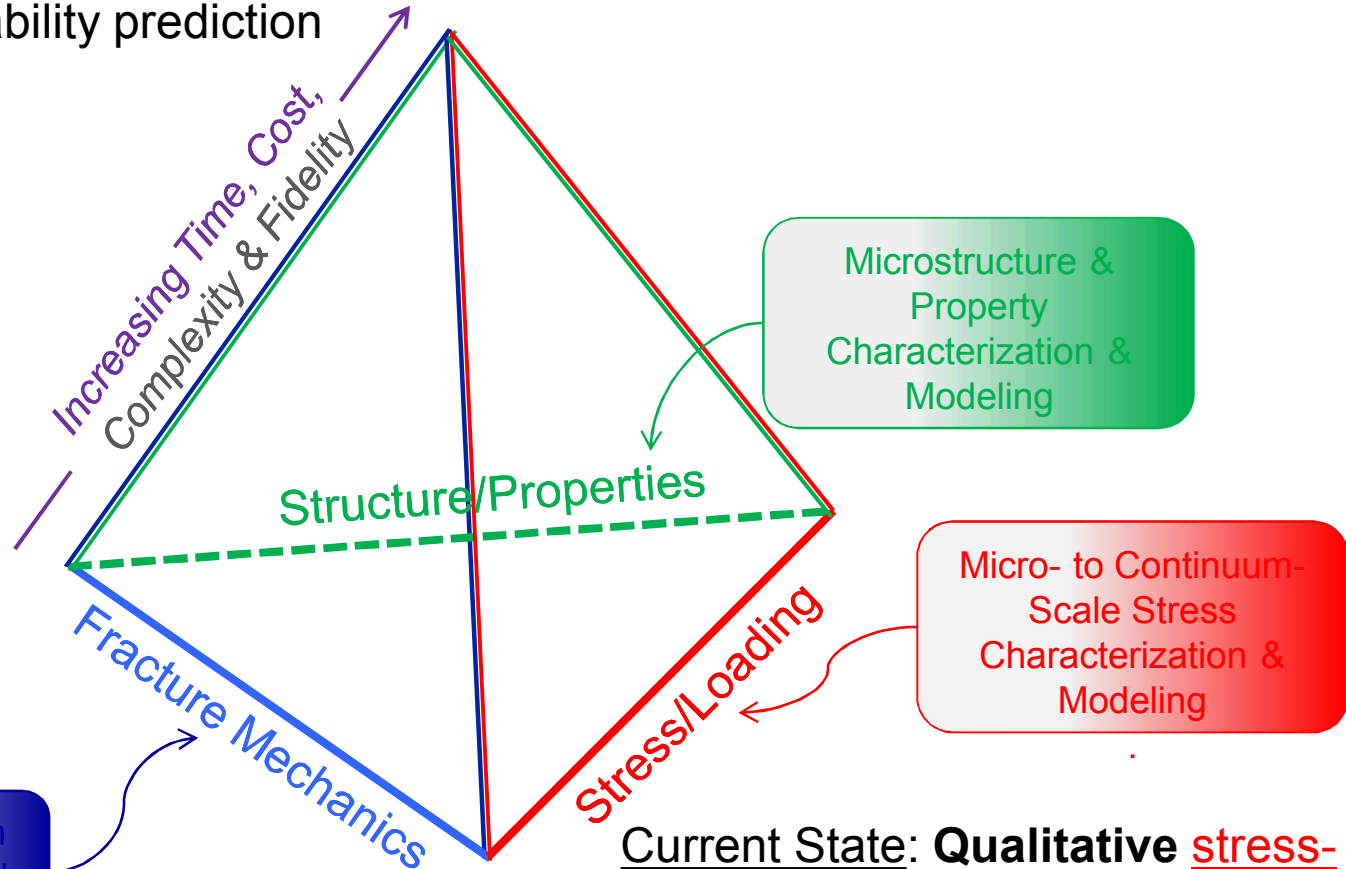
- Transition from **Qualitative** stress-based engineering judgment to **Quantitative** mechanics-based failure prediction.

Approach

- Develop foundational materials characterization & modeling S&T in:
 - 1) **Stress/Loading** – physically-based models, materials & processing data, & model validation
 - 2) **Fracture Mechanics** - crack initiation & propagation, and statistical bounds & variability
 - 3) **Structure/Properties** – understand & control of process-structure-property relations

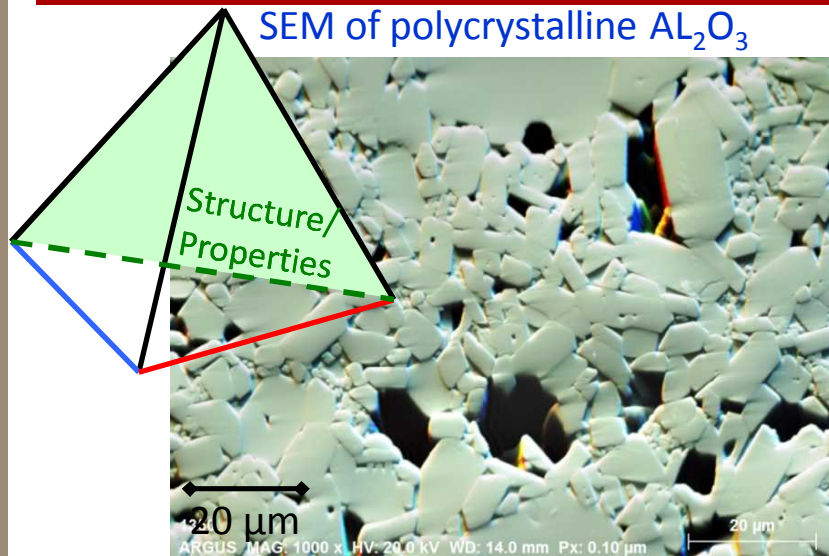
Coordinated **Stress**, **Fracture**, & **Structure/Props** Experiments & Modeling Are Being Conducted

Vision: **Quantitative**
mechanics-based failure &
reliability prediction

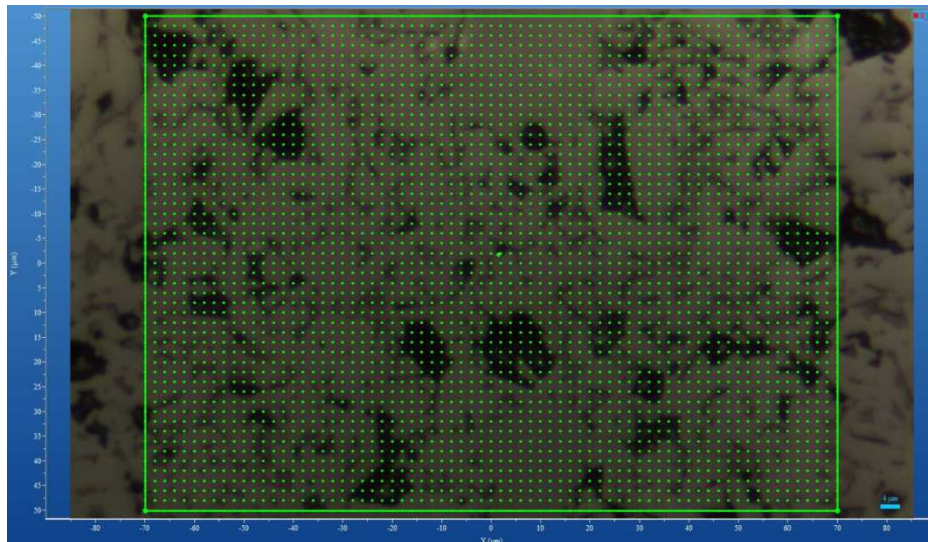


Current State: **Qualitative** stress-based failure analysis
(engineering judgment)

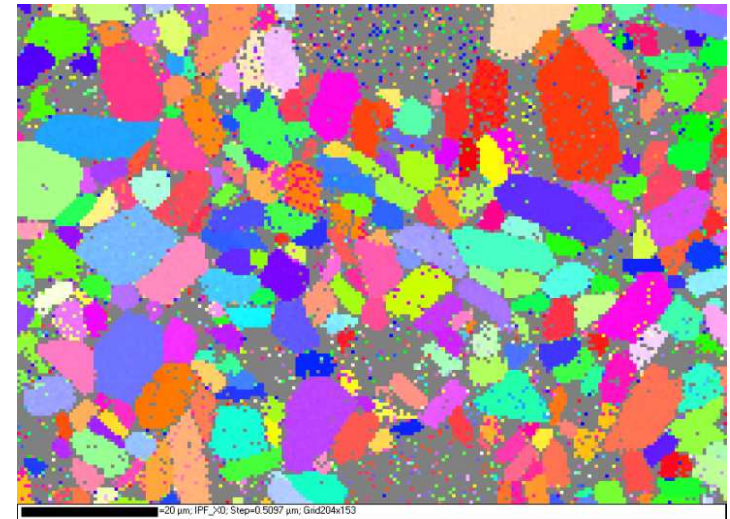
Micro- To Continuum-Scale Stress Mapping Is Possible With SEM/EBSD And PL Spectroscopy



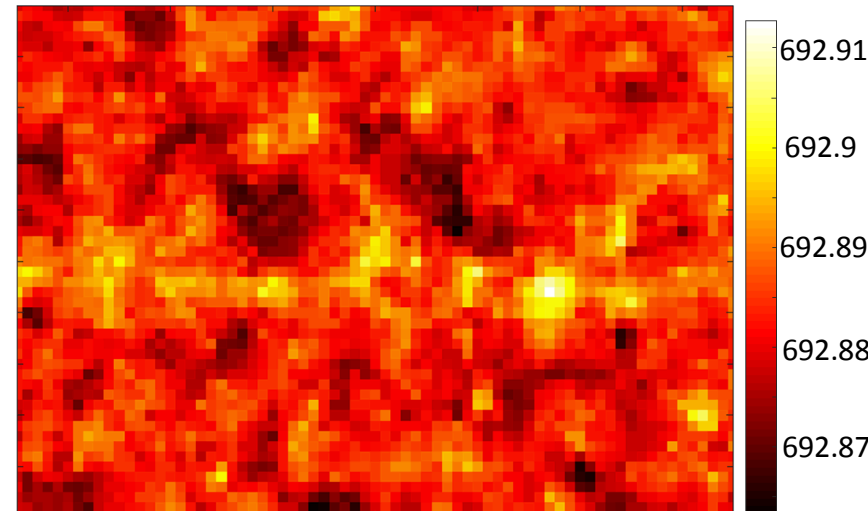
PL Spectroscopy grid (2 μm spacing)



EBSD map (0.5 μm spacing)



R2 peak shift



PL Spectroscopy Was Used To Measure Stress-Sensitive Cr Emission Band Peak Shifts

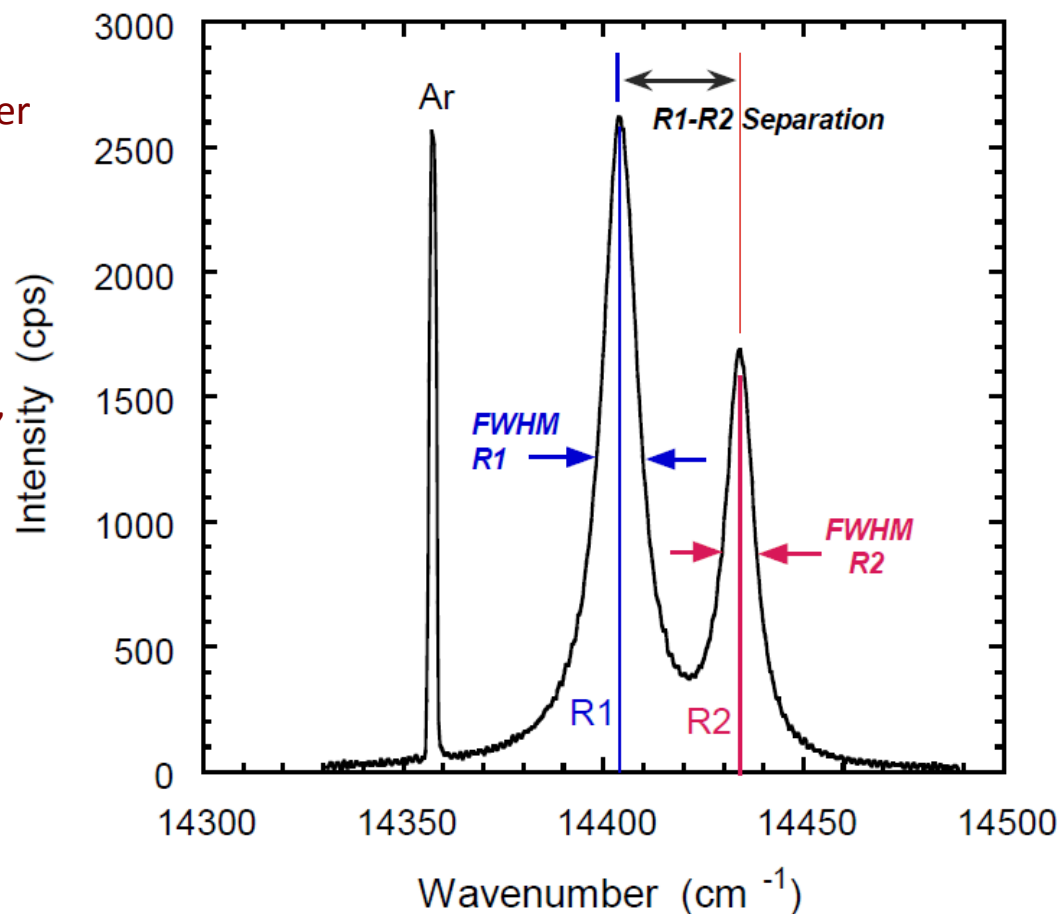
Photoluminescence (PL) Spectroscopy

Equipment

- Horiba Labram HR Raman Spectrometer
- 532 nm, 15 mW Laser
- Confocal microscope

Measurement

- Peaks shift due to stress, temperature, & Cr concentration
- Crystal orientation dependent signal
- R1 – R2 separation variation provides additional stress-state information
- Peak width provides stress-state information
- Ar line corrected instrument drift



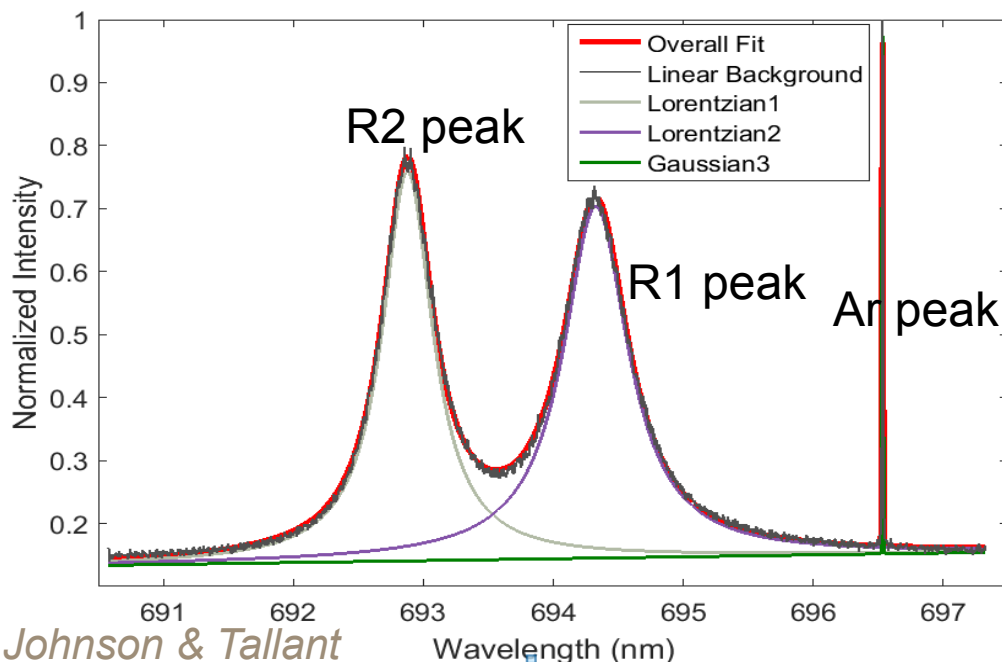
A State-Of-The-Art PL Spectroscopy Capability Has Been Developed To Map Multi-Scale Stress

Map mm² areas using thousands of spectra with micrometer-scale spatial resolution

- Focused laser beam for micro-scale spatial resolution
- Determine stress sensitive R1 (~694.24 nm) and R2 (~692.84 nm) Ruby ($\text{Al}_2\text{O}_3:\text{Cr}^{3+}$) PL bands
- Automated specimen repositioning and spectra acquisition
- Process thousands of spectra in minutes (MATLAB, GRAMS, & LABSPEC)

Wavelength resolution and stability to resolve peak shifts to 0.001 nm (~3MPa)

- Instrument drift corrected to Ar lamp emission line NIST reference (696.5431 nm)
- Temperature stable to 0.1°C (0.0007 nm peak shift) and temperature corrected
- Working to correct for Cr concentration (1 wt.% Cr – 4.8 nm peak shift)



- R1 & R2 fluorescence peaks (positions, widths, and separations) are best fit with a Lorentzian or pseudo-Voigt fit
- The Ar peak is best fit with a Gaussian fit

Converting Peak Shifts to Stress

$$\Delta\nu \text{ (1/cm)} = \Pi_{ij} \left(\frac{\text{cm}^{-1}}{\text{GPa}} \right) \sigma_{ij} (\text{GPa})$$

if $\Pi_{11} = \Pi_{22} = \Pi_a$ and $\Pi_{33} = \Pi_c$ this can be put in the form

$$\begin{bmatrix} \Delta\nu^{(1)} \\ \Delta\nu^{(2)} \end{bmatrix} = \begin{bmatrix} \Pi_M^{(1)} & \Pi_S^{(1)} \\ \Pi_M^{(2)} & \Pi_S^{(2)} \end{bmatrix} \begin{bmatrix} \sigma_M \\ \sigma_S \end{bmatrix} \text{ where } \Pi_M^{(i)} = \Pi_c^{(i)} + 2\Pi_a^{(i)} \quad \Pi_S^{(i)} = \Pi_c^{(i)} - \Pi_a^{(i)}$$

$$\sigma_M = (\sigma_{11} + \sigma_{22} + \sigma_{33})/3 \quad \sigma_S = (2\sigma_{33} - \sigma_{11} - \sigma_{22})/3$$

C. A. Michaels, R. F. Cook, "Determination of residual stress distributions in polycrystalline alumina using fluorescence microscopy" *Materials and Design*, 107, (2016), 478-490

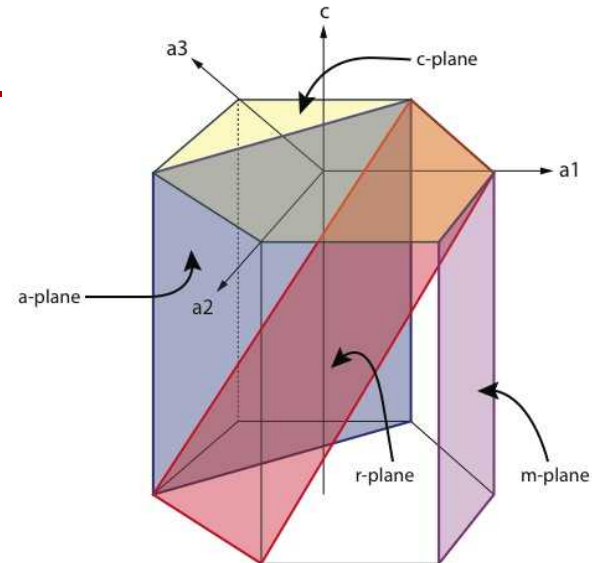
Table I. Piezospectroscopic Coefficients for Ruby

	Piezospectroscopic coefficients (cm ⁻¹ /GPa)						
	Previous results			Our results			
	Uniaxial loading		Hydrostatic loading pressure coeff P^1				$\Pi_{11} + \Pi_{22} + \Pi_{33}$
	Π_{11}	Π_{33}		Π_{11}	Π_{22}	Π_{33}	
R1	3.0 [‡]	1.8 [‡]	7.59 ^{††}	2.56	3.50	1.53	7.59
	3.2 [§]	1.4 [§]					
	2.7 [¶]	1.8 [¶]					
R2	2.8 [‡]	2.3 [‡]	7.615 ^{††}	2.65	2.80	2.16	7.61
	2.8 [§]	1.9 [§]					
	2.4 [¶]	2.2 [¶]					

¹ $P = \Pi_{11} + \Pi_{22} + \Pi_{33}$ [‡]Reference 4, room temperature(?). [§]Reference 7, 77 K. [¶]Reference 6, 77 K. ^{††}Reference 12, room temperature.

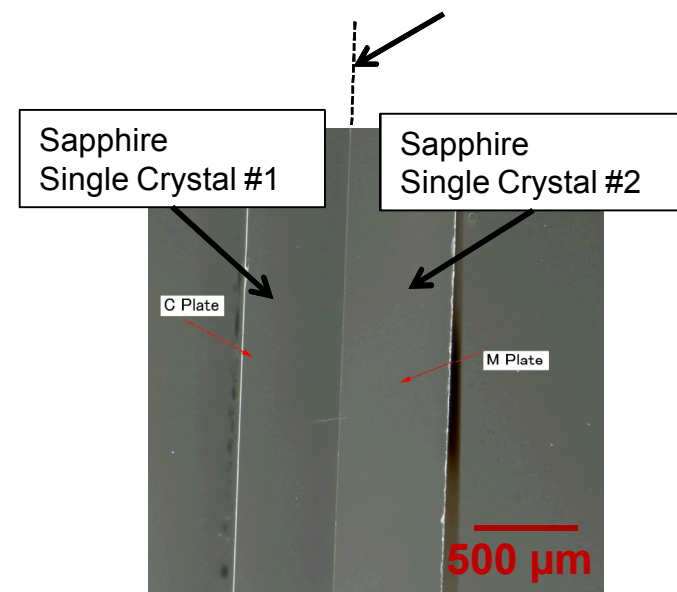
Bi-crystal samples for Spectroscopic stress measurement

- Sputtered ~100nm of glass on polished surface of single crystals (Eagle glass from corning)
- Crystals were then placed glass side together on alumina boat
- Crystals were heated to 1600°C at 20°C/min and held for 1 hr followed by air cool in furnace



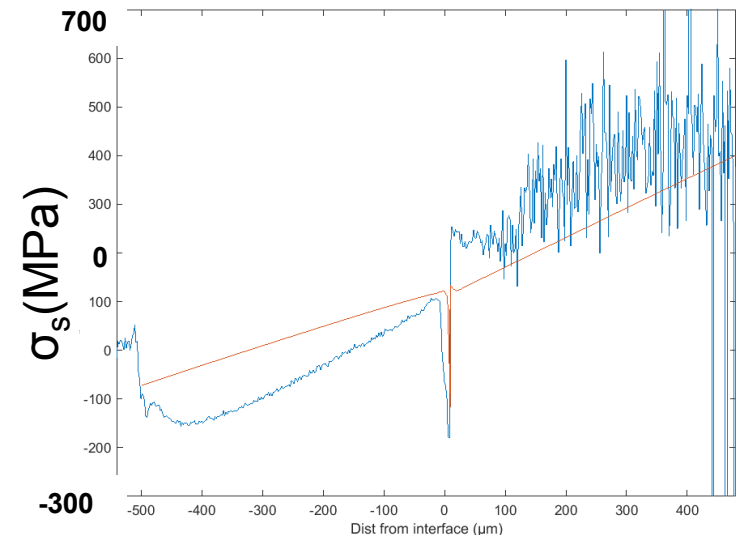
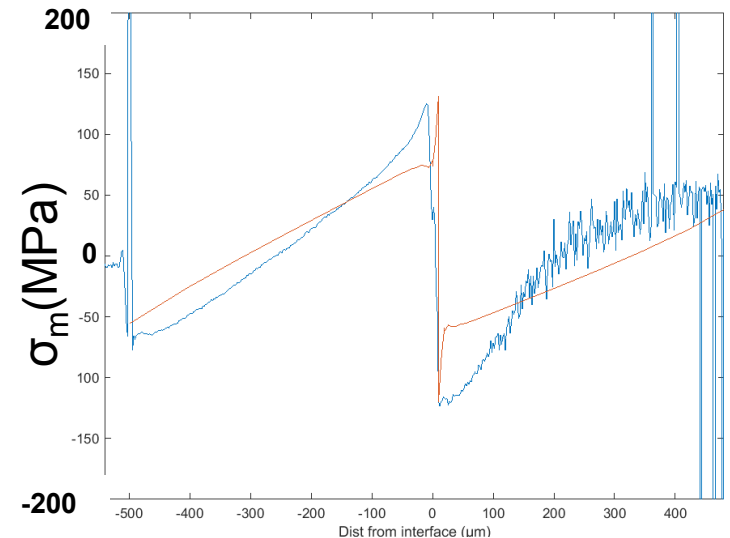
Successfully bonded Bi-crystals:

- C-plane to C-plane, rotated 30°
- A-plane to C-plane
- A-plane to M-plane



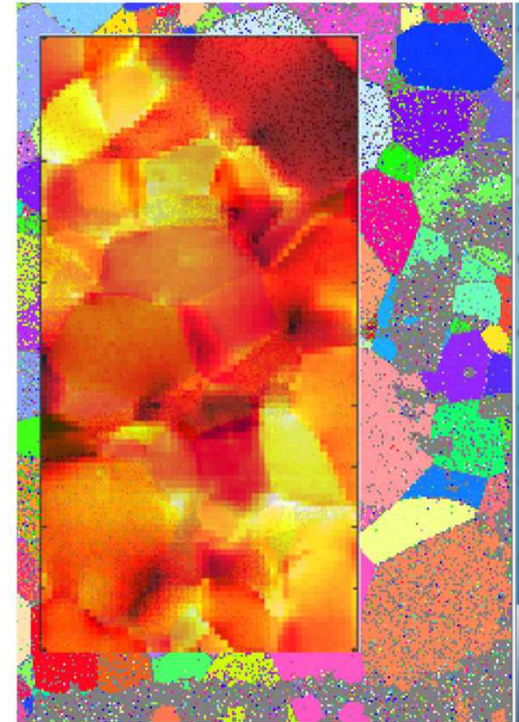
Stress results, compare to FE

- σ_M calculated from PL data has same shape as that from FE model
- There is currently a scaling uncertainty
 - What temperature change should be applied in FE model?
 - This plot uses $\Delta T = 1600^\circ\text{C}$ but glass layer doesn't support stress for high temperatures
 - Currently only using linear, room temperature CTE values



Microstructural Meshing REAL microstructures

- Generated microstructures are often insufficient for model validation with experiments
- Equivalent microstructures is vaguely defined, in order to do first order model validation need microstructure upon which experiments performed

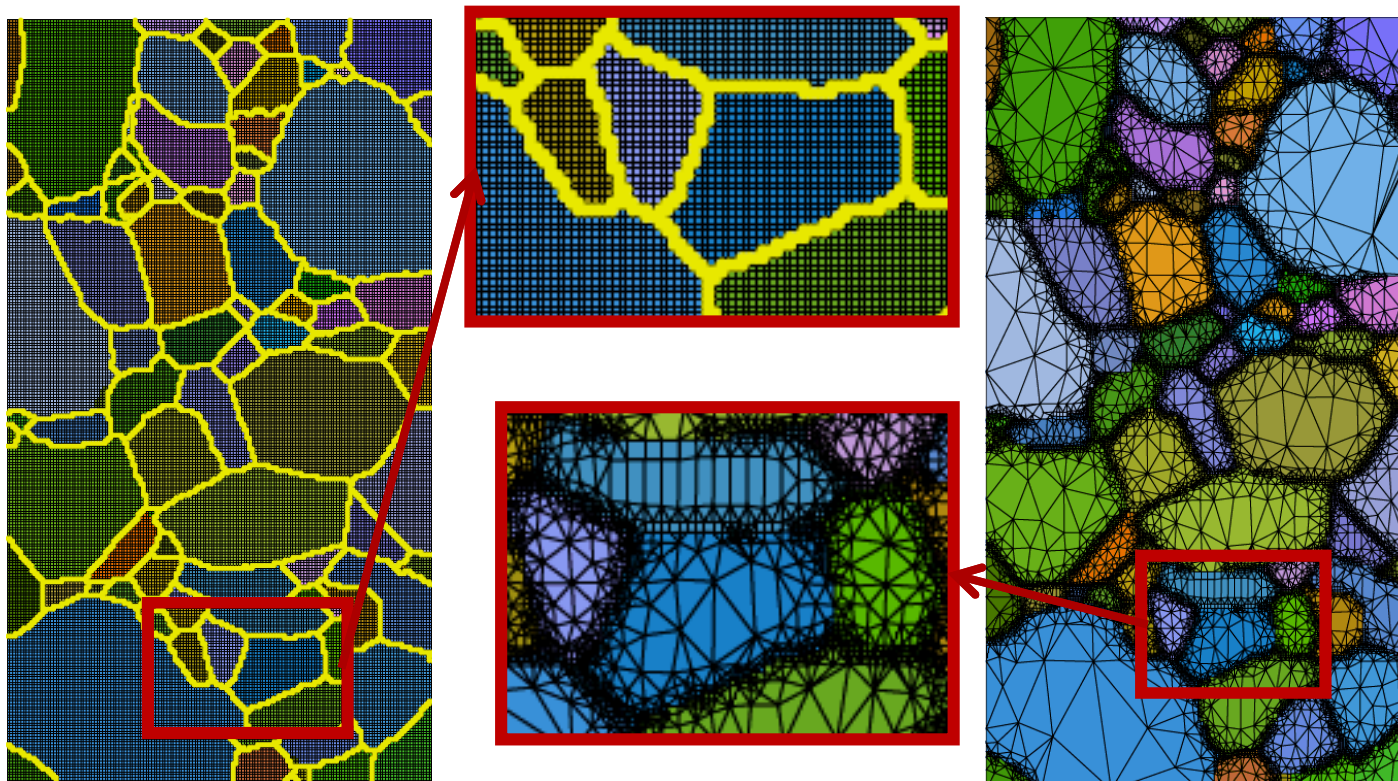


EBSD map aligned with
experiment mapped for stress

Meshing Schemes

- Multiple commercial and open source meshing software's available
- Common issue is number of elements to capture microstructure can become extremely large
- Fall into two basic categories
 - Point-by-point, or element for every pixel/data point
 - Cubit Sculpt, MOOSE EBSD/Image reader, etc
 - Software that enables input from multiple data sources
 - OOF2/3D, Avizo, etc

Comparisons of Meshing Schemes

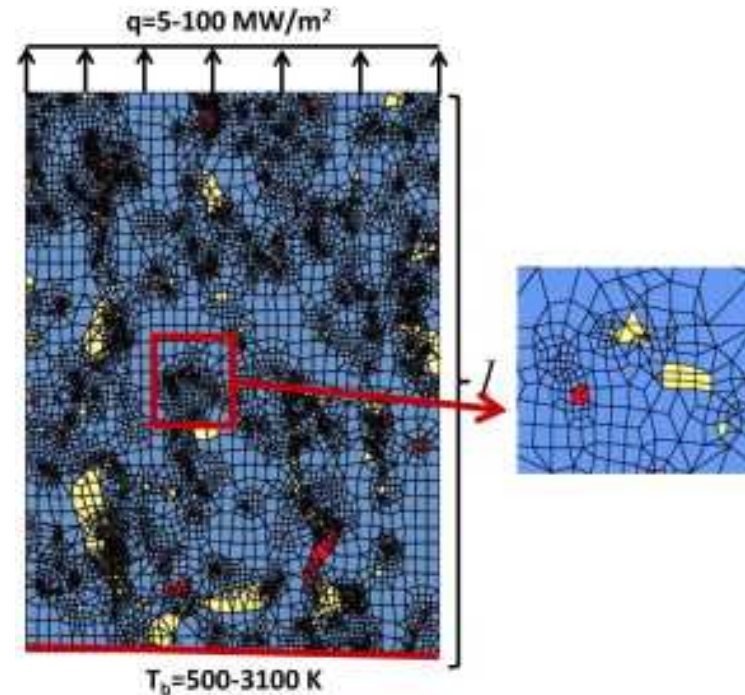


	Element per point	OOF2
N_{elements}	44274	18090
N_{nodes}	43836	27987

Significant reduction in computational power for OOF2 meshes

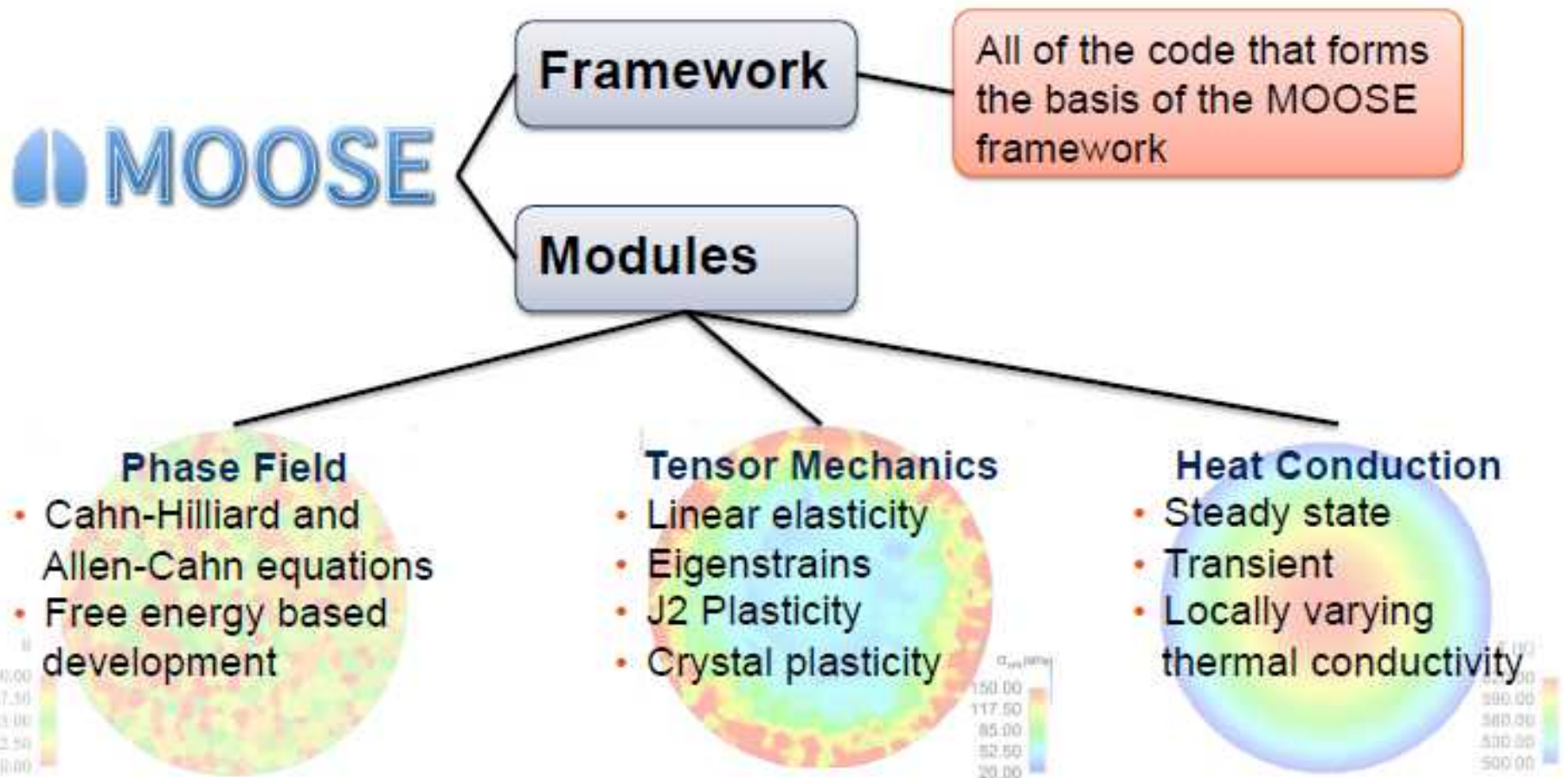
Have your mesh now what?

- Need material properties, including anisotropy
- Need to be able to rotate elasticity and other tensor properties by orientation
- MOOSE is great option for adaptive rapid development



Mesoscale Modeling with the MOOSE framework

- All of the code required to easily create your own phase field application is in the open source MOOSE modules (MOOSE-PF).



Model Set up

elastic constants

$$S_{11} = 497 \text{ GPa} \quad S_{33} = 501 \text{ GPa}$$

$$S_{44} = 147 \text{ GPa} \quad S_{12} = 163 \text{ GPa}$$

$$S_{13} = 116 \text{ GPa} \quad S_{14} = -22 \text{ GPa}$$

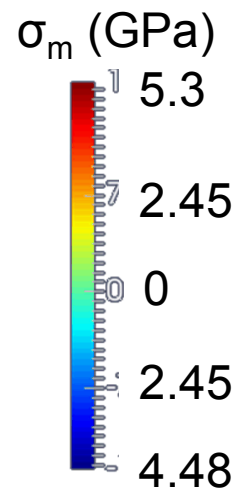
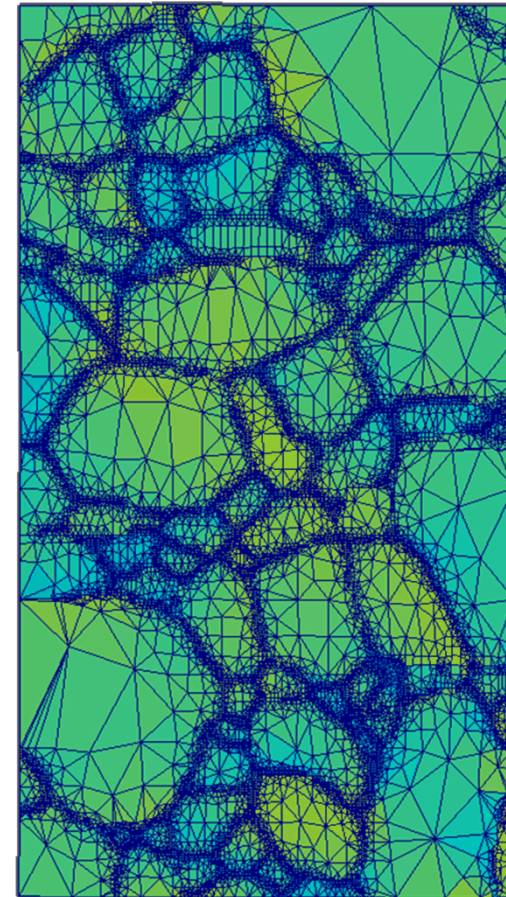
- Goto et. al. Journal of Geophysical Research, 1989

Coefficients of thermal expansion

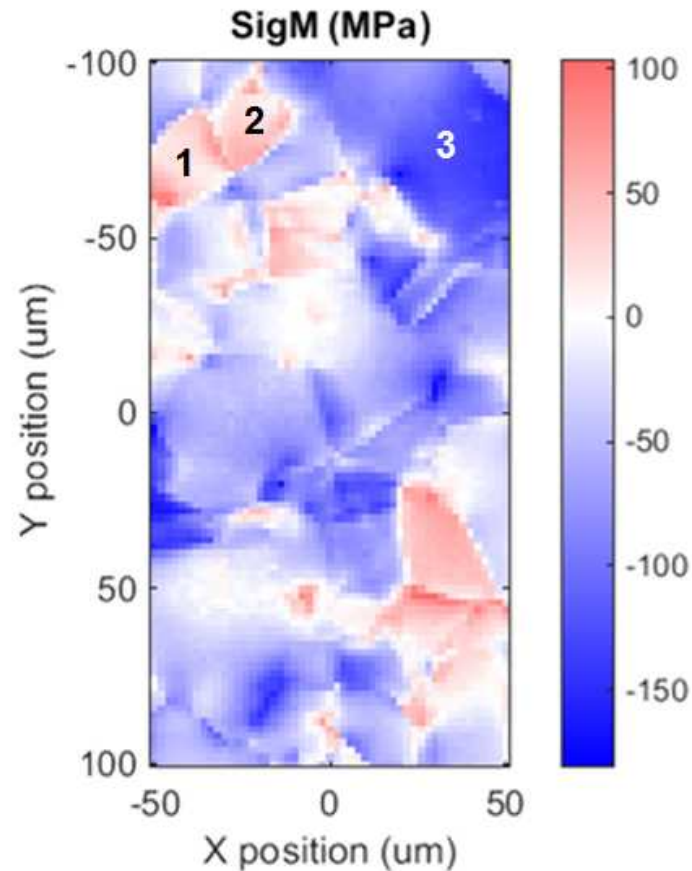
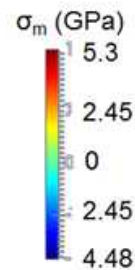
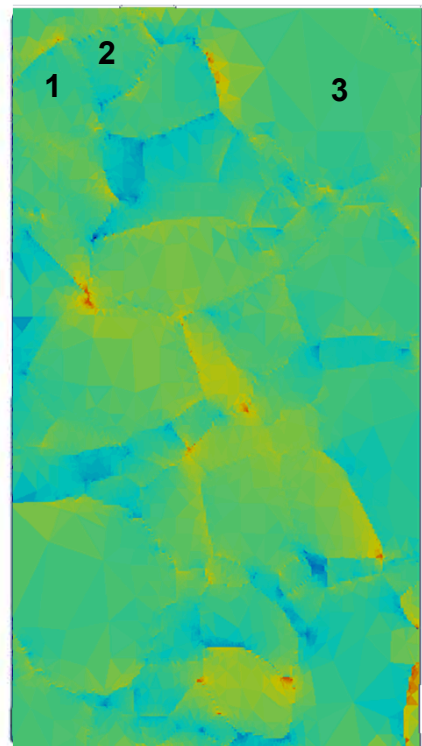
$$\alpha_{11} = 7.3\text{e-}06 \text{ 1/}^\circ\text{C}$$

$$\alpha_{33} = 8.2\text{e-}06 \text{ 1/}^\circ\text{C}$$

$$\Delta T = 1500^\circ\text{C}$$



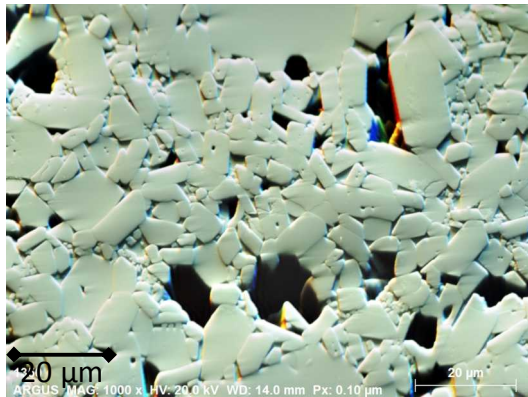
Comparison to Experiment



General Agreement-need to refine
for resolution and 2D-3D reality

Grain	σ_m (MPa)
1	49
2	206
3	-52

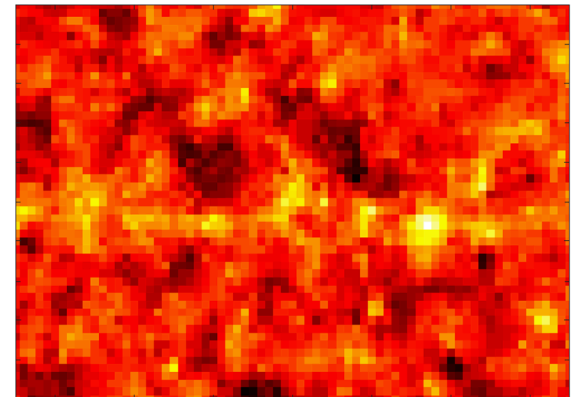
Experimentally-Informed Microstructure Modeling Capability Is Being Developed To Predict Stress



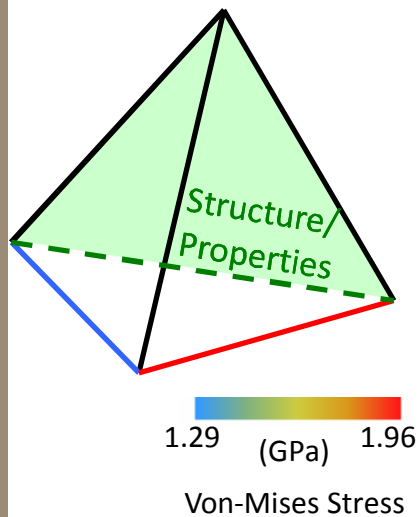
SEM of Al_2O_3



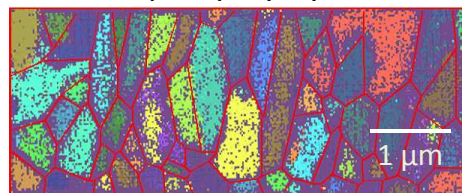
EBSD map of Al_2O_3



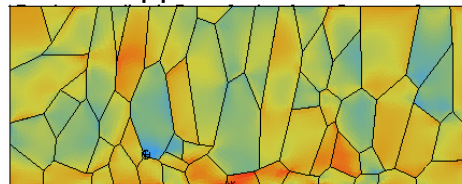
Stress map of Al_2O_3



EBSD map of polycrystalline Si



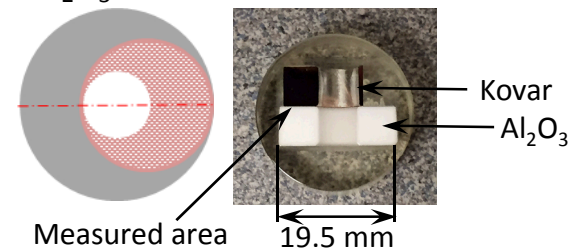
Applied Tension



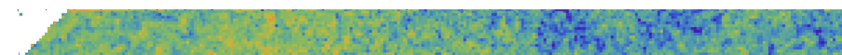
Predicted stress

FE simulation of micro-scale stress & variation in a brittle material microstructure

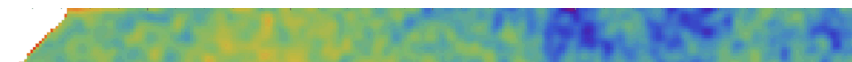
Al_2O_3 – Kovar Brazed Sample



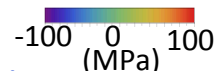
Measurement Grid 3000 μm x 200 μm (10 μm spacing)



Spectroscopic peak shift



Resultant stress calculation



PL spectroscopy used for micro-to continuum-scale stress measurement

Conclusions

- Photo-luminescence spectroscopy mapping is promising technique for enabling validation of stress at critical microstructural level
- Ease/speed of experiments enables large areas to be measured
- Microstructure meshing and modeling are primed to take advantage of this new data to enable mechanistic based models of brittle failure

-
- Perform external loading experiments on single crystals
 - Perform loading experiments on tested microstructures and compare
 - Move to more complicated microstructures
 - Study interaction of loading and microstructure defects/properties
 - Improve models with experimental validation

Questions



Backup Slides

Converting Peak Shifts to Stress

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